- silicon layer having a thickness between the first side and the second side, the thickness of the silicon layer being 30 nm;
- a platinum layer deposited on the first side of the silicon layer;
- a first heterojunction interface between the silicon layer and the platinum layer;
- a cobalt layer deposited on the second side of the silicon layer; and
- a second heterojunction interface between the silicon layer and the cobalt layer.
- **24**. A n-type metal-semiconductor-metal heterojunction diode (MSM diode), comprising:
 - a silicon layer having a first side and a second side opposite the first side, a surface of the first side being doped with phosphorus at a surface concentration of 2×10²⁰ cm⁻³, the silicon layer having a thickness between the first side and the second side, the thickness of the silicon layer being 60 nm;
 - a first chromium layer deposited on the first side of the silicon layer;
 - a first heterojunction interface between the first chromium layer and the silicon layer;
 - a second chromium layer deposited on the second side of the silicon layer; and
 - a second heterojunction interface between the second chromium layer and the silicon layer.

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